

**International Journal of Current
Microbiology and Applied Sciences
(IJCMAS) NAAS RATING-5.38, ICV-95.39**
ISSN: 2319-7692 (Print) ISSN 2319-7706 (Online)

**An International, Monthly, Online, Free Access, Peer Reviewed,
Indexed, fast track Scientific Research Journal**

Certificate of Publication

This is to certify that the following article reviewed by editorial board and published in International Journal of Current Microbiology and Applied Sciences (IJCMAS) ISSN: 2319-7692 (Print) ISSN 2319-7706 (Online).

Int.J.Curr.Microbiol.App.Sci.2020.9.(3):192-197

<https://doi.org/10.20546/ijcmas.2020.903.023>

Character association for yield parameters in Yam bean [Pachyrhizus erosus (L.) Urban]

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International Journal of Current Microbiology and Applied Sciences

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